Abstract Submitted
for the MAR10 Meeting of
The American Physical Society

Pair correlations in semiconductor-superconductor junctions[1]
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[1]This material is based upon work supported by the U.S. DOE, Division of Materials Sciences under Award No. DE-FG02-07ER46453, through the Frederick Seitz Materials Research Laboratory at the University of Illinois at Urbana-Champaign.

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Date submitted: 20 Nov 2009 Electronic form version 1.4